

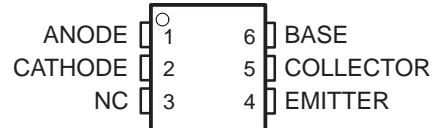
4N35, 4N36, 4N37 OPTOCOUPERS

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COMPATIBLE WITH STANDARD TTL INTEGRATED CIRCUITS

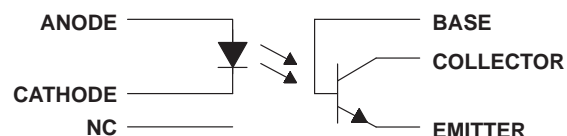
- Gallium-Arsenide-Diode Infrared Source
Optically Coupled to a Silicon npn Phototransistor
- High Direct-Current Transfer Ratio
- High-Voltage Electrical Isolation
1.5-kV, 2.5-kV, or 3.55-kV Rating
- High-Speed Switching
 $t_r = 7 \mu s$, $t_f = 7 \mu s$ Typical
- Typical Applications Include Remote
Terminal Isolation, SCR and Triac Triggers,
Mechanical Relays and Pulse Transformers
- Safety Regulatory Approval
UL/CUL, File No. E65085

DCJT OR 6-TERMINAL DUAL-IN-LINE PACKAGE (TOP VIEW)



†4N35 only
NC – No internal connection

schematic



absolute maximum ratings at 25°C free-air temperature (unless otherwise noted)†

Input-to-output peak voltage (8-ms half sine wave):	4N35	3.55 kV
	4N36	2.5 kV
	4N37	1.5 kV
Input-to-output root-mean-square voltage (8-ms half sine wave):	4N35	2.5 kV
	4N36	1.75 kV
	4N37	1.05 kV
Collector-base voltage		70 V
Collector-emitter voltage (see Note 1)		30 V
Emitter-base voltage		7 V
Input-diode reverse voltage		6 V
Input-diode forward current:		
Continuous		60 mA
Peak (1 μs , 300 pps)		3 A
Phototransistor continuous collector current		100 mA
Continuous total power dissipation at (or below) 25°C free-air temperature:		
Infrared-emitting diode (see Note 2)		100 mW
Phototransistor (see Note 3)		300 mW
Continuous power dissipation at (or below) 25°C lead temperature:		
Infrared-emitting diode (see Note 4)		100 mW
Phototransistor (see Note 5)		500 mW
Operating temperature range, T_A		-55°C to 100°C
Storage temperature range, T_{stg}		-55°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds		260°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. This value applies when the base-emitter diode is open-circuited.
 2. Derate linearly to 100°C free-air temperature at the rate of 1.33 mW/°C.
 3. Derate linearly to 100°C free-air temperature at the rate of 4 mW/°C.
 4. Derate linearly to 100°C lead temperature at the rate of 1.33 mW/°C. Lead temperature is measured on the collector lead 0.8 mm (1/32 inch) from the case.
 5. Derate linearly to 100°C lead temperature at the rate of 6.7 mW/°C.



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

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4N35, 4N36, 4N37 OPTOCOUPERS

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electrical characteristics at 25°C free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{(BR)CBO}$ Collector-base breakdown voltage	$I_C = 100 \mu A$, $I_E = 0$, $I_F = 0$	70†			V
$V_{(BR)CEO}$ Collector-emitter breakdown voltage	$I_C = 10 \text{ mA}$, $I_B = 0$, $I_F = 0$	30†			V
$V_{(BR)EBO}$ Emitter-base breakdown voltage	$I_E = 100 \mu A$, $I_C = 0$, $I_F = 0$	7†			V
I_R Input diode static reverse current	$V_R = 6 \text{ V}$			10†	μA
I_{IO} Input-to-output current	$V_{IO} = \text{rated peak value}$, $t = 8 \text{ ms}$			100	mA
$I_{C(on)}$ On-state collector current	$V_{CE} = 10 \text{ V}$, $I_F = 10 \text{ mA}$, $I_B = 0$	10†			mA
	$V_{CE} = 10 \text{ V}$, $I_F = 10 \text{ mA}$, $I_B = 0$, $T_A = -55^\circ C$	4†			
	$V_{CE} = 10 \text{ V}$, $I_F = 10 \text{ mA}$, $I_B = 0$, $T_A = 100^\circ C$	4†			
$I_{C(off)}$ Off-state collector current	$V_{CE} = 10 \text{ V}$, $I_F = 0$, $I_B = 0$		1	50	nA
	$V_{CE} = 30 \text{ V}$, $I_F = 0$, $I_B = 0$, $T_A = 100^\circ C$			500†	μA
h_{FE} Transistor static forward current transfer ratio	$V_{CE} = 5 \text{ V}$, $I_C = 10 \text{ mA}$, $I_F = 0$		500		
V_F Input diode static forward voltage	$I_F = 10 \text{ mA}$	0.8†		1.5†	V
	$I_F = 10 \text{ mA}$, $T_A = -55^\circ C$	0.9†		1.7†	
	$I_F = 10 \text{ mA}$, $T_A = 100^\circ C$	0.7†		1.4†	
$V_{CE(sat)}$ Collector-emitter saturation voltage	$I_C = 0.5 \text{ mA}$, $I_F = 10 \text{ mA}$, $I_B = 0 \text{ mA}$			0.3†	V
r_{IO} Input-to-output internal resistance	$V_{IO} = 500 \text{ V}$, See Note 6	10 ¹¹ †			Ω
C_{io} Input-to-output capacitance	$V_{IO} = 0$, $f = 1 \text{ MHz}$, See Note 6		1	2.5†	pF

† JEDEC registered data

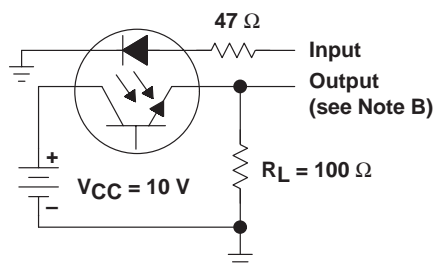
NOTE 6: These parameters are measured between both input-diode leads shorted together and all the phototransistor leads shorted together.

switching characteristics at 25°C free-air temperature†

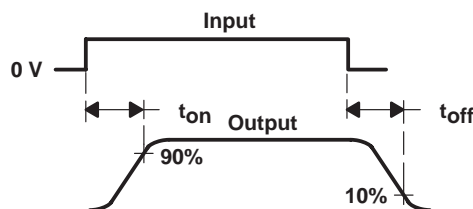
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{on} Time-on time	$V_{CC} = 10 \text{ V}$, $I_{C(on)} = 2 \text{ mA}$, $R_L = 100 \Omega$, See Figure 1		7	10	μs
t_{off} Turn-off time			7	10	

† JEDEC registered data

PARAMETER MEASUREMENT INFORMATION



TEST CIRCUIT



VOLTAGE WAVEFORMS

- NOTES: A. The input waveform is supplied by a generator with the following characteristics: $Z_O = 50 \Omega$, $t_r \leq 15 \text{ ns}$, duty cycle $\approx 1\%$, $t_W = 100 \mu\text{s}$.
B. The output waveform is monitored on an oscilloscope with the following characteristics: $t_r \leq 12 \text{ ns}$, $R_{in} \geq 1 \text{ M}\Omega$, $C_{in} \leq 20 \text{ pF}$.

Figure 1. Switching Times

TYPICAL CHARACTERISTICS

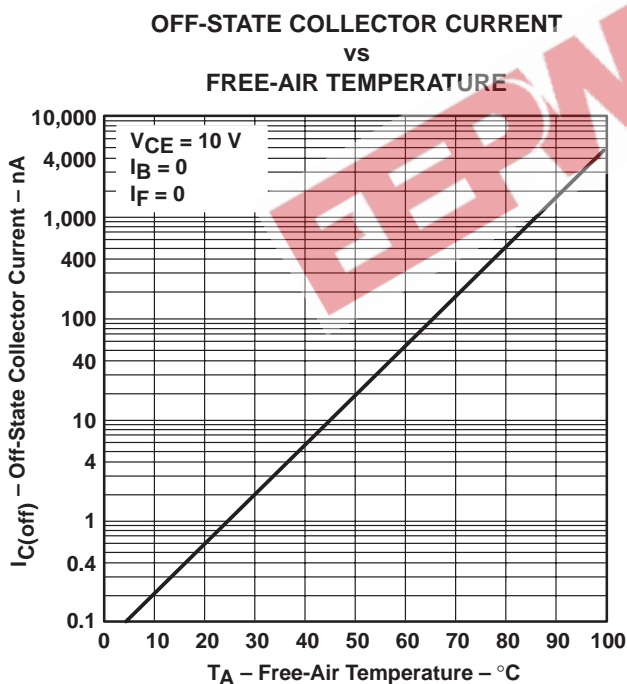


Figure 2

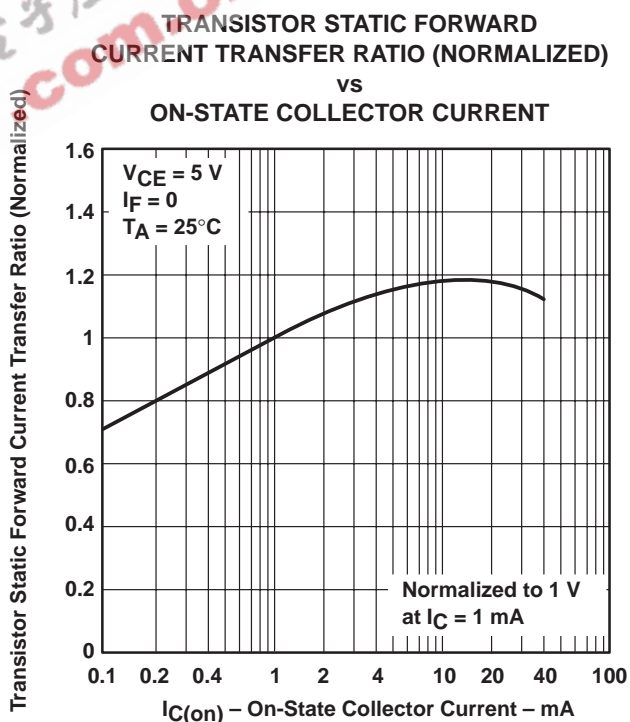


Figure 3

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TYPICAL CHARACTERISTICS

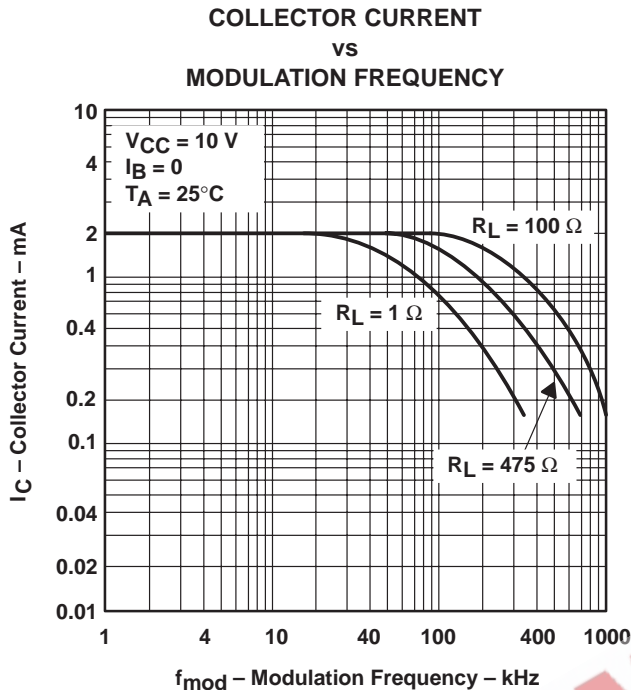


Figure 4

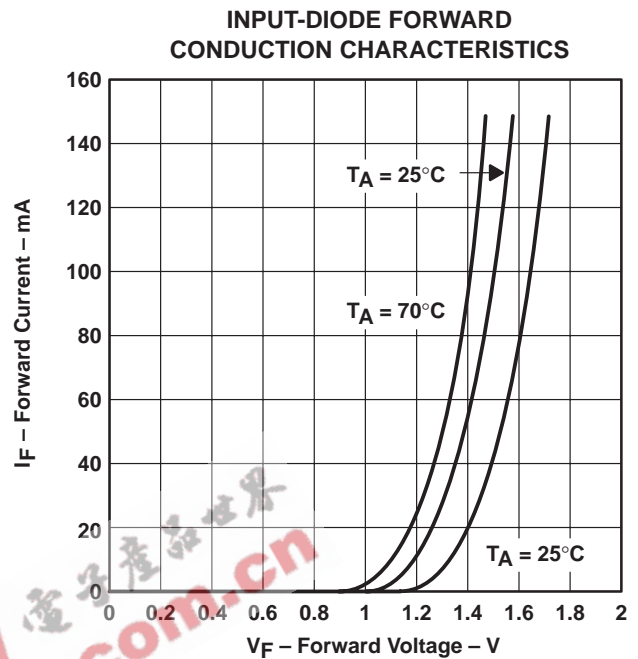


Figure 5

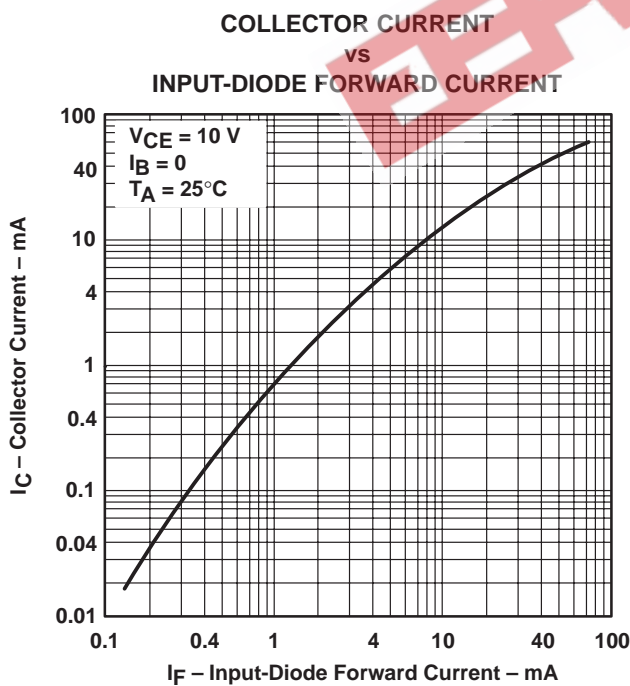


Figure 6

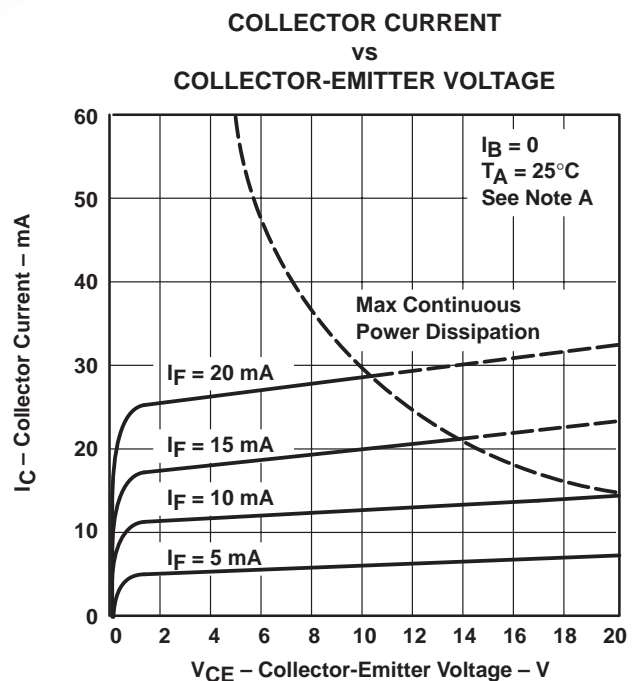
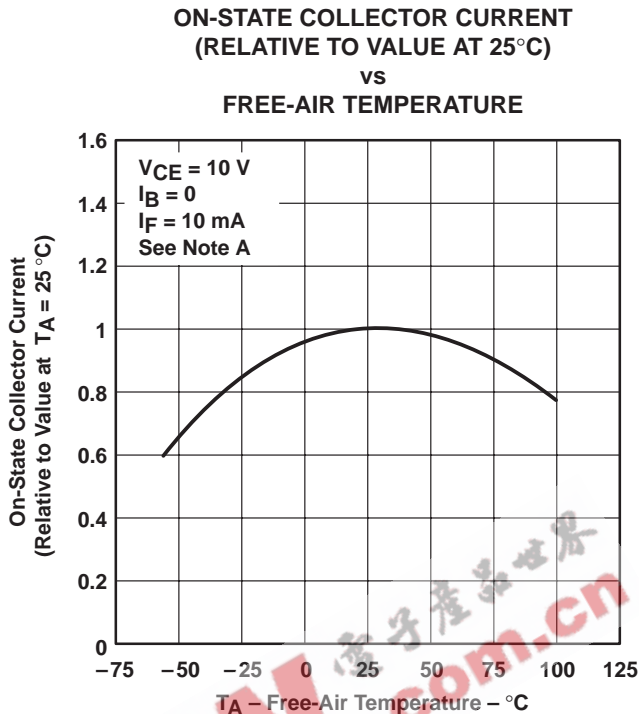


Figure 7

NOTE A. Pulse operation of input diode is required for operation beyond limits shown by dotted lines.

TYPICAL CHARACTERISTICS



NOTE A. These parameters were measured using pulse techniques, $t_W = 1\text{ ms}$, duty cycle $\leq 2\%$.

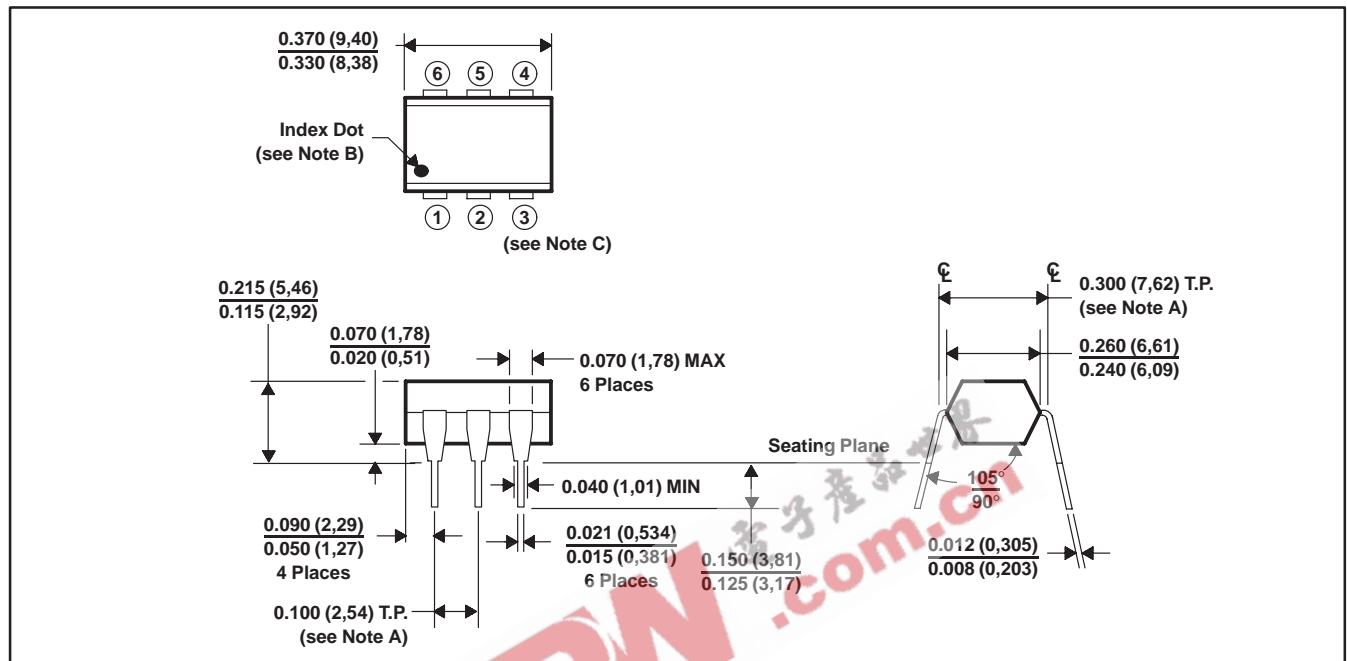
Figure 8

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APPLICATION INFORMATION

The devices consist of a gallium-arsenide infrared-emitting diode and an npn silicon phototransistor. Each device is available in a 6-terminal plastic dual-in-line package, shown in Figure 9, or in a DCJ plastic dual surface-mount optocoupler package (see Mechanical Data).



- NOTES: A. Terminals are within 0.005 (0,13) radius of true position (T.P.) with maximum material condition and unit installed.
 B. Terminal 1 identified by index dot.
 C. The dimensions given fall within JEDEC MO-001 AM dimensions.
 D. All linear dimensions are in inches (millimeters).

Figure 9. Plastic Dual-in-Line Package

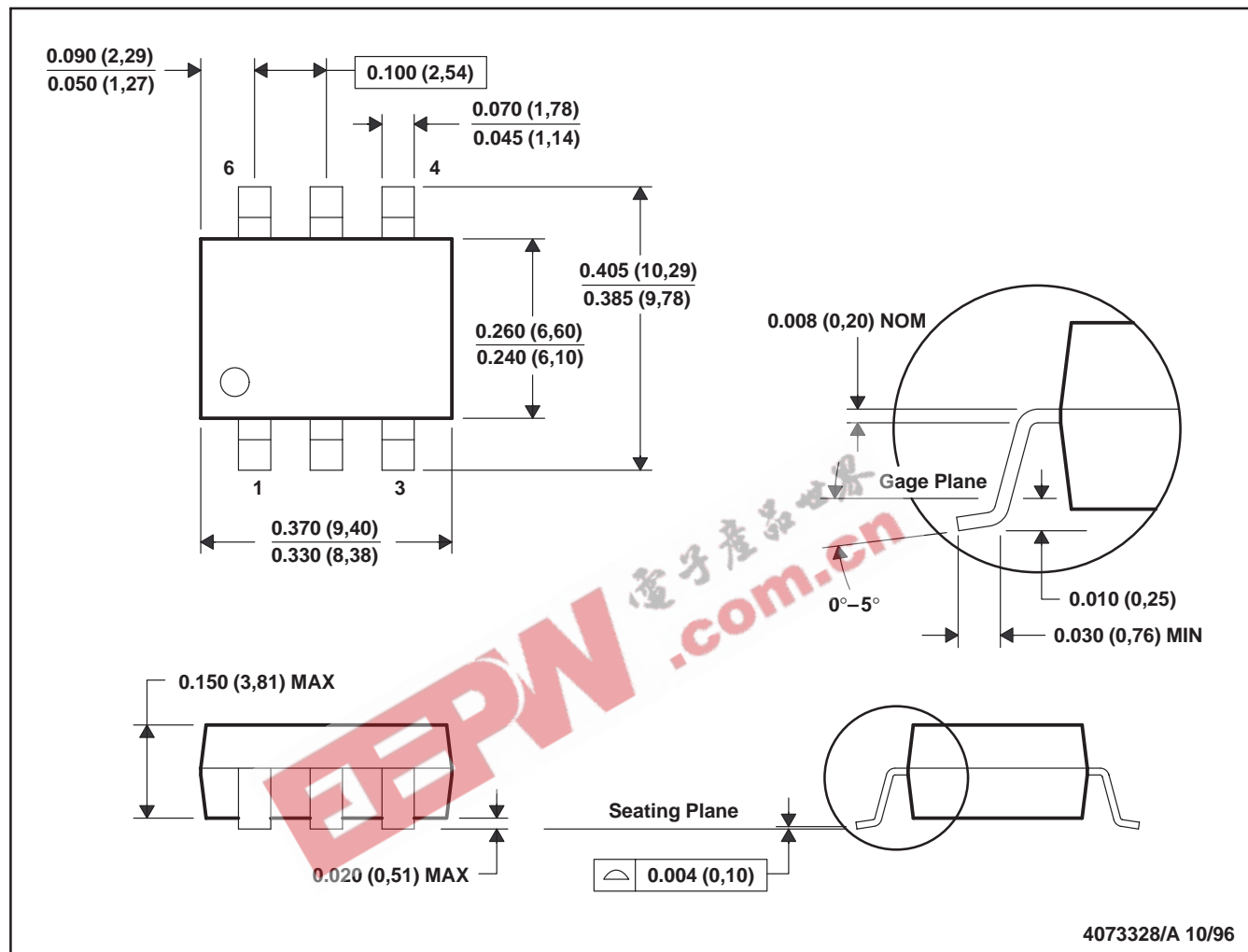
4N35, 4N36, 4N37 OPTOCOUPLEDERS

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MECHANICAL DATA

DCJ (R-PDSO-G6)

PLASTIC DUAL SMALL-OUTLINE OPTOCOUPLER



- NOTES: A. All linear dimensions are in inches (millimeters)
B. This drawing is subject to change without notice.
C. Terminal 1 identified by index dot.

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